

Docket No.: RYUKA.007AUS

Page 1

REQUEST FOR CONTINUED EXAMINATION UNDER 37 CFR 1.114

Applicant(s)

Shin-ichi Hashimoto et al.

App. No.

10/672,469

Filed

September 26, 2003

For

ELECTRON BEAM EXPOSURE APPARATUS, DEFLECTION APPARATUS,

AND ELECTRON BEAM EXPOSURE METHOD

Examiner

Anthony G. Quash

Art Unit

2881

Commissioner for Patents Alexandria, VA 22313-1450

This is a request for continued examination under 37 CFR 1.114 in the above-identified utility patent application.

Enclosed:

- (X) An amendment in twelve (12) pages in response to the office action dated October 5, 2004 which is a bonna fide attempt to advance the application.
- (X) A check in the amount of \$878.00 for RCE fee and one (1) excess independent claim fee (cause by the amendment in the claims concurrently submitted herewith) is enclosed.
- (X) Return prepaid postcard.

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

November 22, 2004

(Date)

Yasuo Muramatsu, Reg. No. 38,684

11/30/2004 RMEBRAHT 00000029 10672469

01 FC:1801 02 FC:1201 790.00 OP 88.00 OP Muramatsu & Associates 7700 Irvine Center Drive Suite 225, Irvine, CA 92618 (949) 753-1127

TRS-RY07.1C1 112204